SN54LS671, SN54LS672, SN74LS671, SN74LS672 4-BIT UNIVERSAL SHIFT REGISTERS/LATCHES WITH 3-STATE OUTPUTS SDLS194 D2638, JANUARY 1981 - REVISED MARCH 1988

4-Bit Universal Shift Registers/Latches

- Multiplexed Outputs for Shift Register or Latched Data
- Choice of Direct SR Clear ('LS671) or Synchronous SR Clear ('LS672)
- 3-State Outputs Drive Bus Lines Directly
- Expandable to Any Word Length

description

The 'LS671 and 'LS672 each contain a 4-bit universal shift register (similar to the 'LS194A) and a 4-bit storage register (similar to the 'LS175) multiplexed to a 3-state output stage (similar to the 'LS258). The user has the option of selecting the shift or storage register via the register/shift select input R/\overline{S} . The 'LS671 has a direct-overriding shift register clear while the 'LS672 features a synchronous shift register clear. The shift register has four distinct modes of operation, namely:

Inhibit clock (do nothing) Shift right (in the direction Ω_A toward Ω_D) Shift left (in the direction Ω_D toward Ω_A) Parallel (broadside) load

A cascade output for the shift register is provided so that full shift register functionality is provided even while the outputs are in the high-impedance mode. The cascade output presents Ω_A data in the shift-left mode, Ω_D data in the shift-right mode.

Both the shift register clock and the latch clock are triggered on the positive transition. The output control (\overline{G}) activates Q_A thru Q_D when low, it places Q_A thru Q_D into the high-impedance state when high.

SN54LS671, SN54LS672 . . . J PACKAGE

SN74LS671, SN74LS672... DW OR N PACKAGE (TOP VIEW)

		1 2 3 4 5 6 7 8 9 10	20 19 18 17 16 15 14 13 12 12		VCC CASC QA QB QC QD S0 S1 G R/S
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SN54LS671, SN54LS672...FK PACKAGE (TOP VIEW)



PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



logic diagram (positive logic)

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Pin numbers shown are for DW, J and N packages.



logic symbols[†]



[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, and N packages.

FUNC	TION	TABL	F
1 0110		100	

					SR	ск_	SER	IAL		PARA	ALLEL		Į	PAR	ALLEL		
			SR N	IODE	S671	S672	INP	UTS		INF	UTS			OUT	PUTS		
G R/S SRCLR	SRCLR	51	SO	, LSA	PST,	SL	SR	A	B	С	D	QA	٥ß	Q _C	٥ _D	CASC [‡]	
Ļ	L	L	×	×	x	1	x	×	×	×	×	×	L	L	L	L	(‡)
L	L	н	х	×	L	L	×	х	х	x	×	х	0 _{A0}	a _{B0}	QC0	a _{D0}	(‡)
L	L	н	L	L	х	х	x	X ,	x	х	х	х	QA0	0 ₈₀	o_{C0}	a _{D0}	н
L	٤	н	L	н	t	1	х	н	x	х	х	x	н	a _{An}	Ω _{Bn}	Q _{Cn}	0 _{Cn}
L	L	н	L	н	t	+	х	L	х	х	х	х) L	QAn	0 _{Bn}	Q _{Cn}	Ω _{Cn}
L	L	н	н	L	÷	t	н	X	х	X	X	×	QBn	Q _{Cn}	Q _{Dn}	н	QBn
L	L	н	н	L	-	t	L	x	х	х	×	х	0 _{Bn}	QCn	Q _{Dn}	L	a _{Bn}
L	L	н	н	н	•	t	х	X	а	b	С	d	а	b	с	đ	н
н	X) ×	Ļ	н	t	T]	x	X	X	×	х	х	z	Z	Z	z	QCu
H	x	X	н	L	1	t	X	X	х	X	x	X	z	Z	Z	z	0 _{Bn}
L	н	×	x	×	х	x	x	×	x	х	х	х	Inte	ernal regis	ter conte	nts	(‡)

H = high level (steady state)

L = low level (steady state)

X = irrelevant (any input, including transitions)

† = transition from low to high level

a, b, c, d = the level of steady-state input at A, B, C, or D, respectively

 Q_{AO} , Q_{BO} , Q_{CO} , Q_{DO} = the level of Q_A , Q_B , Q_C , or Q_D , respectively, before the indicated steady-state input conditions were established $Q_{A\Pi}$, $Q_{B\Pi}$, $Q_{C\Pi}$ = the level of Q_A , Q_B , or Q_C , respectively, before the most-recent transition of the clock Z = high-impedance state

⁺ The cascade output displays the D bit of the shift register in mode 1 (S1, S0 = L, H), the A bit in mode 2 (S1, S0 = HL), and is inactive (H) in modes 0 and 3 (S1, S0 = LL and HH).



schematics of inputs and outputs

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage V _{CC} (see Note 1)	7 V
Input voltage	7 V
Off-state output voltage	
Operating free-air temperature range: SN54LS671, SN54LS672	25°C
SN74LS671, SN74LS672	70°C
Storage temperature range -65° C to 19	50°C

NOTE 1: Voltage values are with respect to the network ground terminal.

recommended operating conditions

				SN54LS	ř _		Γ		
			MIN	NOM	MAX	MIN	NOM	мах	דואט ן
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
1		Cascade out	1		- 0.4			- 0.4	
OH	High-level output current	Q _A , Q _B , Q _C , Q _D	1		- 1			- 2.6	mA
1	Low-level output current	Cascade out	1		4			8	Am
'OL	cownever og påt carrent	Q _A , Q _B , Q _C , Q _D	T		12	1		24] """
tw	Width of SRCK, RCK, or SRCLF	('LS671 only) input pulse	30			30			ns
tsu	Inactive state setup time	SRCLR before SRCK 1 ('LS671 onty)	30			30	-		ns
		S0 or S1 to SRCK 1	45			45			1
		SRCLR + ('LS672 only) to SRCK †	25			25]
t _{su}	Setup time	A, B, C, D to SRCK 1	30			30			ns
		SRCK f to RCK f	30			30			1
		SER to SRCK 1	35			35			
^t h	Hold time	Any input from SRCK †	0			0			ns
TA	Operating free-air temperature		- 65	_	125	0		70	°C



					· · · · · · · · · · · · · · · · · · ·					1		
	DADA	METED		TEST CON		SN54LS	<u> </u>			UNIT		
	PARAMETER		TEST CUN	MIN	TYP [‡]	MAX	MIN	TYP‡	MAX			
VIH	High-level input	voltage				2			2			V
VIL	Low-level input	voltage						0.7	1		0.8	v
VIK	Input clamp vol	tage		V _{CC} = MIN, I	= -18 mA			-1.5	1		-1.5	V
			$a_A - a_D$	V _{CC} = MIN,	I _{OH} = -1 mA	2.4	3.1		1			
۷он	High-level outpu	ut voltage	$\Omega_A \sim \Omega_D$	V _{IH} = 2 V,	¹ OH =2.6 mA				2.4	3.1		l v
			CASC	VIL = VIL max	I _{OH} ≈400 µA	2.5	3.2		2.7	3.2]
			$Q_A - Q_D$		I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
. .	1		$Q_A - Q_D$	$A - Q_D = V_{CC} = MIN, I_{OL} = 24 \text{ mA}$	1	0.35	0.5					
VOL Low-level output	but voltage	CASC	V _{IH} = 2 V	loL = 4 mA		0.25	0.4		0.25	0.4	- ×	
			CASC		IOL = 8 mA				1	0.35	0.5	1
	Off-state output	Current,	0.0-	V _{CC} = MAX,		_		20	T		20	μA
югн	high-level voltag	e applied	$Q_A - Q_D$	V _{IH} = 2 V,	VIL = VIL max			20			20	μμ
1	Off-state output	current,	0. 0.	V _{CC} = MAX,	Vo = 0.4 V,			-20			-20	Aبر
IOZL	low-level voltage	applied	$O_A - O_D$	VIH = 2 V.	V _{1L} = V _{1L} max			-20			-20	μя
t.	Input current at	maximum		Vcc=MAX,				0.1	Γ		0,1	mΑ
II 	input voltage			VCC - MAA,	vi- / v			0.1			Q. 1	
ін	High-level input	current		V _{CC} = MAX,	Vj = 2.7 V			20			20	μA
1	Low-fevel input	current	A, B, C, D	VCC = MAX,	V1 = 0.4 V			- 0.4			-0.4	mA
ԿԵ	Low-level impor	corrent	All others	VCC - MMAA,	vi - 0.4 v			0.2			-0.2	
	Short-circuit ou	cuit output current § QA -		VCC = MAX,	V0 = 0 V	-30		-130	-30		-130	mA
los		ipor currents	CASC		·U-V·	-20		-100	-20		_100	
		All outputs low		V _{CC} = MAX,	See Note 2		35	70		35	70	
lcc	Supply current	All outputs I	nigh	All outputs	See Note 3		30	65		30	65	mA
		QA thru QD	, at Hi-Z	open	See Note 4		37	70	1	37	70	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

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[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ^{*}All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

 $m ^8$ Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

- NOTES: 2. ICCL is tested after two 0-V to 4.5 V to 0-V pulses have been applied to \$RCK and RCK while S0 is at 4.5 V and all other inputs are grounded.
 - 3, ICCH is tested after two 4.5-V to 0-V to 4.5 V pulses have been applied to SACK and ACK while all other inputs are at 4.5 V.
 - 4. I_{CCZ} is tested after two 0-V to 4.5-V to 0-V pulses have been applied to SRCK and RCK while S0 and \overline{G} are at 4.5 V and all other inputs are grounded.



	FROM	то	TEST CON	DITIONS		'LS67'	1		'LS67:	2		
PARAMETER	(INPUT)	(OUTPUT)	MODE	LOAD	MIN	TYP	MAX	MIN	түр	MAX	רואט	
tPLH	CDCK A					31	45		31	45	ns	
^t PHL	SRCK 1		SHIFT LEFT			14	25		14	25		
tPLH	50, S1	CASCADE	OR RIGHT	$R_{L} = 2 k\Omega,$		11	20		12	20	ns	
^t PHL	JU, 31	CASCADE		CL = 15 pF		11	20		12	20		
TPHL	SRCK 1]	SR CLEAR						19	30	ns	
tPHL	SRCER +		SHOLLAN	1		19	30				ns	
^t PLH			SHIFTLEFT			10	20		10	20	ns	
TPHL			OR RIGHT			16	25		16	25		
^t PLH	SRCK t		SR LOAD	1		10	20		10	20	កទ	
^t PHL		1	3H LOAD	Į	[15	25		15	25	175	
^t PHL				SR CLEAR						17	30	ns
tPHL .	SRCLR +		Sh CLLAN			21	30				ាទ	
^t PLH	RCK t	a _A - a _D	LATCH	$R_{L} = 667 \Omega$,		10	20		10	20	ns	
^t ₽HL	HUK I		CATCH	С _L = 45 рF		15	25		15	25		
TPLH	R/S †]	[12	25		13	25	ns
t₽HL	H/3 I				A1117			15	25	<u> </u>	15	25
^t PLH	R/S↓		MUX			17	25		17	25	ns	
[†] PHL	R/3↓			1		16	25		16	25] ""	
^t PZH	Ğ i		3-STATE	1		16	25		16	25	ns	
^t PZL	G 1		ENABLE	1	[19	30	1	19	30] '''	
^t PHZ	<u>Ē</u> t		3-STATE	RL≖667Ω,	· · · ·	16	25		16	25	ns	
TPLZ	чī		DISABLE	CL = 5 pF		16	25	<u> </u>	16	25] "	

switching characteristics, VCC = 5 V, TA = 25° C, see note 5

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.

TYPICAL APPLICATION DATA

The 'LS671 or 'LS672 can easily be expanded utilizing the cascade output and the SER L and SER R inputs. A typical expansion is shown below.



FIGURE 1 - 'LS671, 'LS672 EXPANDED TO 12 BITS, (3 PACKAGES)

Any desired word length may be obtained using the scheme shown. Corresponding control pins of all the packages are tied in common, i.e., all S0 pins are connected together, all S1 pins are connected together, etc.



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